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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 30-5004(4015) 33507

December 16, 1999

SERIAL NO. 09/465,492

LIST OF ART CITED BY APPLICANT

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APPLICANT
Vladimir Segal et al.

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GROUP 1742

ADEMARKE				U.S. PATENT DOCUMENTS			
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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		Document Number	Date	Country	Class	Subclass	Translation Yes No
ЙM	AM	7-90566	04/95	Japan			х
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MM	AO	8-64554	03/96	Japan			х
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FORM PTO-1449	Attorney Docket Number	33507/VGG
	Application Number	to be assigned 09/465,492
INFORMATION DISCLOSURE	Filing Date	Herewith
STATEMENT BY APPLICANT	Applicant(s)	Vladimir M. Segal et al.
(	Group Art Unit	to be assigned 1742
(use as many sheets as necessary)	Examiner Name	to be assigned

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OTHER DOCUMENTS					
EXAMINER INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
MW	C. Klein et al., "Manual of Mineralogy", pp 39-40				
AH	S. Wright et al. "Effect of Annealing Temperature on the Texture of Rolled Tantalum and Tantalum-10 Wt.% Tungsten, reprinted from Tungsten and Refractory Metals 2, pp 501-508				
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EXAMINER SIGNATURE	Haurs William 1 DATE CONSIDERED 3-1-01				
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					